

Top: Adjusted grating.

Cover: Sentinel 5 - grating.

Department
Micro- and Nanostructured Optics

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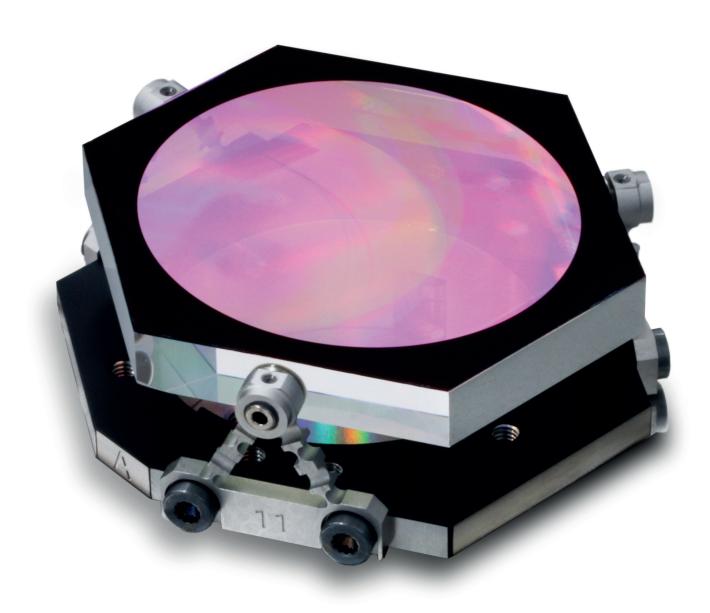




Fraunhofer Institute for Applied Optics and Precision Engineering IOF



High-performance diffraction gratings for spectrometer applications



High-performance diffraction gratings for spectrometer applications

Near Infrared Reflection Grating with iso-static mount to the mechanical interface frame.

## **Features**

Customized diffraction gratings are designed, manufactured with lithographic technologies, machined for mechanical interface, assembled and fully characterized with respect to their optical parameters.

## **Parameters**

■ Reflection (R) or Transmission (T)

Line density: 10 to 3500 l/mm

– Polarization: TE, TM or unpolarized

down to < 2 %

■ Channels: UV, VIS, NIR, SWIR1/2/3

Bandwidth:

- Low resolution 200-600 nm

- High resolution 50-200 nm

■ Element size: < 260 x 120 mm² or

< 200 x 200 mm<sup>2</sup> or

< 270 mm diameter

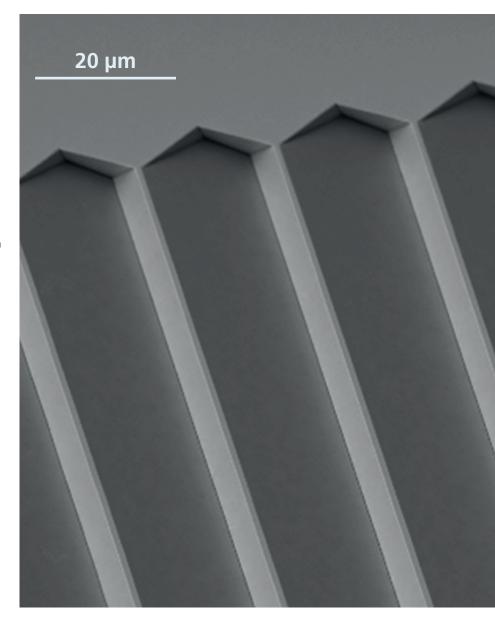
■ Efficiency depends on grating configuration

## Service / technology

- Grating design
- Lithographic wafer-level processing
  - Electron beam lithography
  - Reactive ion etching and/or wet chemical etching
- Characterization
  - Diffraction efficiency
  - Wave front error
  - Stray light
- Machining of mechanical interface
- Backside anti-reflection coating (T)
- Aperture-stop coating
- Bonding / Assembly

## References

- ESA GAIA mission
- Sentinel 4 mission



SEM micrograph of an Echelle grating in silicon with 20 microns period.